

Title (en)

DEVICE FOR CHARACTERISING ELECTRIC OR ELECTRONIC COMPONENTS

Title (de)

EINRICHTUNG ZUM CHARAKTERISIEREN VON ELEKTRISCHEN ODER ELEKTRONISCHEN KOMPONENTEN

Title (fr)

DISPOSITIF POUR LA CARACTERISATION DE COMPOSANTS ELECTRIQUES OU ELECTRONIQUES

Publication

EP 2382480 A1 20111102 (FR)

Application

EP 09804285 A 20090122

Priority

- FR 2009001472 W 20091222
- FR 0807450 A 20081224

Abstract (en)

[origin: WO2010072924A1] The invention relates to an integrated device (PM) for characterising electric or electronic components (DUT), in particular nanometric ones, comprising a substantially insulating substrate (S) on which are provided four conducting pads (P1, P2, P3, P4), at least three resistive pads (R1, R3, R4) connecting said pads together, and a transmission line (CPW) including a signal conductor (CC) and at least one ground conductor (CL1, CL2), wherein: said resistive pads are arranged so as to connect a first conducting pad to a second and a fourth conducting pad, and to connect said fourth conducting pad to a third conducting pad; the signal conductor of the transmission line is connected to the first conducting pad; and the ground conductor of the transmission line is connected to the third pad.

IPC 8 full level

G01R 27/28 (2006.01)

CPC (source: EP US)

G01R 27/28 (2013.01 - EP US); **G01R 35/005** (2013.01 - EP US)

Citation (search report)

See references of WO 2010072924A1

Designated contracting state (EPC)

AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO SE SI SK TR

DOCDB simple family (publication)

FR 2940458 A1 20100625; **FR 2940458 B1 20110304**; EP 2382480 A1 20111102; US 2012092032 A1 20120419; WO 2010072924 A1 20100701

DOCDB simple family (application)

FR 0807450 A 20081224; EP 09804285 A 20090122; FR 2009001472 W 20091222; US 200913142007 A 20091222